

ISO7240CF, ISO7240C, ISO7240M ISO7241C, ISO7241M ISO7242C, ISO7242M

SLLS868H-SEPTEMBER 2007-REVISED OCTOBER 2008

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HIGH SPEED QUAD DIGITAL ISOLATORS

FEATURES

- Selectable Failsafe Output (ISO7240CF)
- 25 and 150-Mbps Signaling Rate Options
 - Low Channel-to-Channel Output Skew;
 1 ns Max
 - Low Pulse-Width Distortion (PWD);2 ns Max
 - Low Jitter Content; 1 ns Typ at 150 Mbps
- Typical 25-Year Life at Rated Working Voltage (see application note SLLA197 and Figure 17)
- 4000-V_{peak} Isolation, 560-V_{peak} V_{IORM}
 - UL 1577, IEC 60747-5-2 (VDE 0884, Rev 2),
 IEC 61010-1 and CSA Approved

- 4 kV ESD Protection
- Operate With 3.3-V or 5-V Supplies
- High Electromagnetic Immunity (see application report SLLA181)
- -40°C to 125°C Operating Range

APPLICATIONS

- Industrial Fieldbus
- Computer Peripheral Interface
- Servo Control Interface
- Data Acquisition

DESCRIPTION

The ISO7240, ISO7241 and ISO7242 are quad-channel digital isolators with multiple channel configurations and output enable functions. These devices have logic input and output buffers separated by Tl's silicon dioxide (SiO₂) isolation barrier. Used in conjunction with isolated power supplies, these devices block high voltage, isolate grounds, and prevent noise currents from entering the local ground and interfering with or damaging sensitive circuitry.

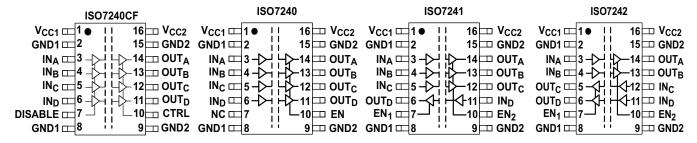
The ISO7240 has all four channels in the same direction while the ISO7241 has three channels the same direction and one channel in opposition. The ISO7242 has two channels in each direction.

The C option devices have TTL input thresholds and a noise-filter at the input that prevents transient pulses from being passed to the output of the device. The M option devices have CMOS Vcc/2 input thresholds and do not have the input noise-filter or the additional propagation delay.

The ISO7240CF has an input disable function on pin 7, and a selectable high or low failsafe-output function with the CTRL pin (pin 10). The failsafe-output is a logic high when a logic-high is placed on the CTRL pin or it is left unconnected. If a logic-low signal is applied to the CTRL pin, the failsafe-output becomes a logic-low output state. The ISO7240CF input disable function prevents data from being passed across the isolation barrier to the output. When the inputs are disabled, the outputs are set by the CTRL pin.

These devices may be powered from either 3.3-V or 5-V supplies on either side in any 3.3-V / 3.3-V, 5-V / 5-V / 5-V / 3.3-V, or 3.3-V / 5-V combination. Note that the signal input pins are 5-V tolerant regardless of the voltage supply level being used.

These devices are characterized for operation over the ambient temperature range of -40°C to 125°C.





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

Table 1. Device Function Table ISO724x (1)

INPUT V _{CC}	OUTPUT V _{CC}	INPUT (IN)	OUTPUT ENABLE (EN)	OUTPUT (OUT)
		Н	H or Open	Н
PU	PU	L	H or Open	L
PU	FU	X	٦	Z
		Open	H or Open	Н
PD	PU	X	H or Open	Н
PD	PU	X	L	Z

(1) PU = Powered Up; PD = Powered Down; X = Irrelevant; H = High Level; L = Low Level

Table 2. ISO7240CF Function Table

V _{CC1}	V _{CC2}	DATA INPUT (IN)	DISABLE INPUT (DISABLE)	FAILSAFE CONTROL INPUT (CTRL)	DATA OUTPUT (OUT)
PU	PU	Н	L or Open	X	Н
PU	PU	Г	L or Open	X	L
Х	PU	X	Н	H or Open	Н
Х	PU	X	Н	L	L
PD	PU	X	X	H or Open	Н
PD	PU	X	X	L	L

AVAILABLE OPTIONS

PRODUCT	SIGNALING RATE	INPUT THRESHOLD	CHANNEL CONFIGURATION	MARKED AS	ORDERING NUMBER ⁽¹⁾
ISO7240CDW	25 Mbps	~1.5 V (TTL)		ISO7240C	ISO7240CDW (rail)
13072400000	25 Mibbs	(CMOS compatible)		13072400	ISO7240CDWR (reel)
ICO7240CF	25 Mbno	~1.5 V (TTL)	4/0	ISO7240CF	ISO7240CFDW (rail)
ISO7240CF	25 Mbps	(CMOS compatible)	4/0	1507240CF	ISO7240CFDWR (reel)
ISO7240MDW	150 Mbps	Vee/2 (CMOS)		ISO7240M	ISO7240MDW (rail)
1507240IVIDVV	150 Mbps	Vcc/2 (CMOS)		1507240W	ISO7240MDWR (reel)
ISO7241CDW	25 Mbno	~1.5 V (TTL)		ISO7241C	ISO7241CDW (rail)
1507241CDW	25 Mbps	(CMOS compatible)	3/1	15072410	ISO7241CDWR (reel)
ISO7241MDW	150 Mbps	Voo/2 (CMOS)	3/1	ISO7241M	ISO7241MDW (rail)
1307241111011	150 Mbps	Vcc/2 (CMOS)		1307241101	ISO7241MDWR (reel)
ISO7242CDW	25 Mbno	~1.5 V (TTL)		ISO7242C	ISO7242CDW (rail)
1507242CDW	25 Mbps	(CMOS compatible)	2/2	15072420	ISO7242CDWR (reel)
ICO7242MDW/	150 Mbpo	Vec/2 (CMOS)	2/2	ISO7242M	ISO7242MDW (rail)
ISO7242MDW	150 Mbps	Vcc/2 (CMOS)		1307242101	ISO7242MDWR (reel)

⁽¹⁾ For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.



ABSOLUTE MAXIMUM RATINGS(1)

					VALUE	UNIT
V_{CC}	Supply voltag	ge ⁽²⁾ , V _{CC1} , V _{CC2}			-0.5 to 6	V
VI	Voltage at IN	, OUT, EN, DISABLE, CTRL			-0.5 to 6	V
I _O Output current					±15	mA
		Human Body Model	JEDEC Standard 22, Test Method A114-C.01		±4	
ESD	Electrostatic discharge	Field-Induced-Charged Device Model	JEDEC Standard 22, Test Method C101	All pins	±1	kV
		Machine Model	ANSI/ESDS5.2-1996	1	±200	V
T_{J}	Maximum jun	ction temperature			170	°C

⁽¹⁾ Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS

			MIN	TYP	MAX	UNIT
V_{CC}	Supply voltage ⁽¹⁾ , V _{CC1} , V _{CC2}		3.15		5.5	V
I _{OH}	High-level output current				4	mA
I _{OL}	Low-level output current		-4			mA
	lanut aulaa width	ISO724xC	40			20
1/t _{ui} Signaling rate	ISO724xM	6.67	5		ns	
4 /4	Cinnaling sets	ISO724xC	0	30 ⁽²⁾	25	Maria
1/t _{ui}		ISO724xM	0	200(2)	150	Mbps
V_{IH}	High-level input voltage (IN)	100704-114	0.7 V _{CC}		V_{CC}	V
V_{IL}	Low-level input voltage (IN)	ISO724xM	0		0.3 V _{CC}	V
V_{IH}	High-level input voltage (IN, DISABLE, CTRL, EN)	10072420	2		V _{CC}	V
V_{IL}	Low-level input voltage (IN, DISABLE, CTRL, EN)	ISO724xC	0		0.8	V
T_{J}	Junction temperature				150	°C
Н	External magnetic field-strength immunity per IEC 61000-4-8 and IEC 61000-4-9 certification				1000	A/m

⁽¹⁾ For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V.

⁽²⁾ All voltage values are with respect to network ground terminal and are peak voltage values.

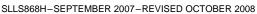
⁽²⁾ Typical value at room temperature and well-regulated power supply.



ELECTRICAL CHARACTERISTICS: V_{CC1} and V_{CC2} at 5-V $^{(1)}$ OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
SUPPL	Y CURRENT			1		,		
	10070400/M	Quiescent	V _I = V _{CC} or 0 V, All channels, no load,		1	3	A	
	ISO7240C/M	25 Mbps	EN ₂ at 3 V		7	10.5	mA	
	ISO7241C/M	Quiescent	V _I = V _{CC} or 0 V, All channels, no load,		6.5	10	mA	
I _{CC1}	1307241C/W	25 Mbps	EN ₁ at 3 V, EN ₂ at 3 V		12	18	ША	
	ICO7242C/M	Quiescent	V _I = V _{CC} or 0 V, All channels, no load,		10	16	A	
	ISO7242C/M	25 Mbps	EN ₁ at 3 V, EN ₂ at 3 V		15	24	mA	
	1007240C/M	Quiescent	V _I = V _{CC} or 0 V, All channels, no load,		15	22	A	
	ISO7240C/M	25 Mbps	EN ₂ at 3 V		17	25	mA	
	ISO7241C/M	Quiescent	V _I = V _{CC} or 0 V, All channels, no load,		13	20	mA	
I _{CC2}	1307241C/W	25 Mbps	EN ₁ at 3 V, EN ₂ at 3 V		18	28	ША	
	ISO7242C/M	Quiescent	V _I = V _{CC} or 0 V, All channels, no load,		10	16	mA	
	13072420/W	25 Mbps	EN ₁ at 3 V, EN ₂ at 3 V		15	24	ША	
ELECT	RICAL CHARACTERISTICS							
I _{OFF}	Sleep mode output currer	nt	EN at 0 V, Single channel		0		μΑ	
W	High lovel output voltage		I _{OH} = -4 mA, See Figure 1	$V_{CC} - 0.8$			V	
V _{OH}	High-level output voltage		I _{OH} = -20 μA, See Figure 1	V _{CC} - 0.1			V	
V	Low-level output voltage		I _{OL} = 4 mA, See Figure 1			0.4	V	
V_{OL}	Low-level output voltage		I _{OL} = 20 μA, See Figure 1			0.1	V	
$V_{I(HYS)}$	Input voltage hysteresis				150		mV	
I _{IH}	High-level input current		IN from 0 V/ to V/			10		
I _{IL}	Low-level input current		IN from 0 V to V _{CC}	-10			μΑ	
Cı	Input capacitance to grou	nd	IN at V _{CC} , V _I = 0.4 sin (4E6πt)		2		pF	
CMTI	Common-mode transient	immunity	V _I = V _{CC} or 0 V, See Figure 5	25	50		kV/μs	

⁽¹⁾ For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V.







SWITCHING CHARACTERISTICS: V_{CC1} and V_{CC2} at 5-V OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay	10072440		18		42	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	ISO724xC	Soo Figure 4			2.5	ns
t _{PLH} , t _{PHL}	Propagation delay	ISO724xM	See Figure 1	10		23	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	150724XIVI			1	2	ns
	Dort to part alray (2)	ISO724xC				8	
t _{sk(pp)}	Part-to-part skew ⁽²⁾	ISO724xM			0	3	ns
	Observation of a state of all (3)	ISO724xC				2	
t _{sk(o)}	Channel-to-channel output skew (3)	ISO724xM			0	1	ns
t _r	Output signal rise time	,	0.00 500000 4		2		
t _f	Output signal fall time		See Figure 1		2		ns
t _{PHZ}	Propagation delay, high-level-to-high-imped	dance output			15	20	
t _{PZH}	Propagation delay, high-impedance-to-high	-level output	0 Finance 0		15	20	
t _{PLZ}	Propagation delay, low-level-to-high-imped	ance output	See Figure 2		15	20	ns
t _{PZL}	Propagation delay, high-impedance-to-low-	level output			15	20	,
t _{fS}	Failsafe output delay time from input powe	r loss	See Figure 3		12		μs
t _{wake}	Wake time from input disable		See Figure 4		15		μs
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO724xM	150 Mbps NRZ data input, Same polarity input on all channels, See Figure 6		1		ns

⁽¹⁾ Also referred to as pulse skew.

⁽²⁾ t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

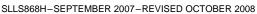
⁽³⁾ t_{sk(o)} is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.



ELECTRICAL CHARACTERISTICS: V_{CC1} at 5-V, V_{CC2} at 3.3-V⁽¹⁾ OPERATION

	PARAMETI	ER	TEST CONDIT	IONS	MIN	TYP	MAX	UNIT	
SUPPL	Y CURRENT								
	10070400/14	Quiescent		1		1	3		
	ISO7240C/M	25 Mbps	$V_I = V_{CC}$ or 0 V, All channels, r	no load, EN ₂ at 3 V		7	10.5	mA	
	10070440/84	Quiescent	V _I = V _{CC} or 0 V, All channels, r	no load, EN₁ at 3 V,		6.5	10	A	
I _{CC1}	ISO7241C/M	25 Mbps	EN ₂ at 3 V			12	18	mA	
	10070400/M	Quiescent	V _I = V _{CC} or 0 V, All channels, r	no load, EN₁ at 3 V,		10	16	A	
	ISO7242C/M	25 Mbps	EN ₂ at 3 V			15	24	mA	
	ICO7040C/M	Quiescent	\/ \/ or 0 \/ All abannala r	as load EN at 2 V		9.5	15	A	
	ISO7240C/M	25 Mbps	$V_I = V_{CC}$ or 0 V, All channels, r	10 10au, EN2 at 3 V		10.5	17	mA	
	ISO7241C/M	Quiescent	V _I = V _{CC} or 0 V, All channels, r	no load, EN ₁ at 3 V,		8	13	mA	
I _{CC2}	13072410/10	25 Mbps	EN ₂ at 3 V		11.5	18	IIIA		
	ISO7242C/M	Quiescent	V _I = V _{CC} or 0 V, All channels, r	no load, EN ₁ at 3 V,		6	10	mA	
	13072420/101	25 Mbps	EN ₂ at 3 V			9	14	IIIA	
ELECT	RICAL CHARACTI	ERISTICS							
I _{OFF}	Sleep mode outp	out current	EN at 0 V, Single channel			0		μΑ	
				ISO7240	V _{CC} - 0.4				
V_{OH}	High-level output	voltage	I _{OH} = -4 mA, See Figure 1	ISO724x (5-V side)	V _{CC} - 0.8			V	
			$I_{OH} = -20 \mu A$, See Figure 1		V _{CC} - 0.1				
\/	Low lovel output	voltogo	I _{OL} = 4 mA, See Figure 1				0.4	V	
V_{OL}	Low-level output	voltage	I_{OL} = 20 μ A, See Figure 1				0.1	V	
V _{I(HYS)}	Input voltage hys	teresis				150		mV	
I _{IH}	High-level input of	current	INI from O V/ to V/				10	^	
I _{IL}	Low-level input c	urrent	IN from 0 V to V _{CC}		-10			μΑ	
C _I	Input capacitance	e to ground	IN at V_{CC} , $V_{I} = 0.4 \sin (4E6\pi t)$			2		pF	
CMTI	Common-mode t immunity	ransient	V _I = V _{CC} or 0 V, See Figure 5		25	50		kV/μs	

⁽¹⁾ For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V.







SWITCHING CHARACTERISTICS: V_{CC1} at 5-V, V_{CC2} at 3.3-V OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
t _{PLH} , t _{PHL}	Propagation delay	1007040	See Figure 1	20		50		
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	ISO724xC				3	ns	
t _{PLH} , t _{PHL}	Propagation delay	ISO724xM		12		29		
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}				1	2	ns	
	Dort to part alcour (2)	ISO724xC				10		
t _{sk(pp)}	Part-to-part skew (2)	ISO724xM			0	5	ns	
	(3)	ISO724xC				3		
t _{sk(o)}	Channel-to-channel output skew (3)	ISO724xM			0	1	ns	
t _r	Output signal rise time		0		2			
t _f	Output signal fall time		See Figure 1		2		ns	
t _{PHZ}	Propagation delay, high-level-to-high-imped	dance output			15	20		
t _{PZH}	Propagation delay, high-impedance-to-high	-level output	0		15	20		
t _{PLZ}	Propagation delay, low-level-to-high-impeda	ance output	See Figure 2		15	20	ns	
t _{PZL}	Propagation delay, high-impedance-to-low-	level output			15	20		
t _{fs}	Failsafe output delay time from input power	· loss	See Figure 3		18		μs	
t _{wake}	Wake time from input disable		See Figure 4		15		μs	
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO724xM	150 Mbps PRBS NRZ data input, Same polarity input on all channels, See Figure 6		1		ns	

⁽¹⁾ Also known as pulse skew

⁽²⁾ t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

⁽³⁾ t_{sk(o)} is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.



ELECTRICAL CHARACTERISTICS: V_{CC1} at 3.3-V, V_{CC2} at 5-V⁽¹⁾ OPERATION

	PARAMETE	R	TEST CONDIT	TIONS	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT							
	10070400/M	Quiescent	V _I = V _{CC} or 0 V, All channels,	no load, EN ₂ at 3 V		0.5	1	A
	ISO7240C/M	25 Mbps				3	5	mA
	ISO7241C/M	Quiescent	$V_1 = V_{CC}$ or 0 V, All channels, EN_2 at 3 V	no load, EN ₁ at 3 V,		4	7	mA
I _{CC1}		25 Mbps				6.5	11	
	ISO724C/M	Quiescent	$V_1 = V_{CC}$ or 0 V, All channels, EN_2 at 3 V	no load, EN ₁ at 3 V,		6	10	mA
		25 Mbps				9	14	
	10070400/M	Quiescent	V _I = V _{CC} or 0 V, All channels,	no load, EN ₂ at 3 V		15	22	A
	ISO7240C/M	25 Mbps				17	5 1 3 5 4 7 5 11 6 10 9 14 5 22 7 25 8 20 8 28 0 16 5 24 0 0.1	mA
	ISO7241C/M	Quiescent	$V_1 = V_{CC}$ or 0 V, All channels, EN_2 at 3 V	no load, EN ₁ at 3 V,		13		mA
I _{CC2}		25 Mbps				18	28	
	ISO7242C/M	Quiescent	$V_1 = V_{CC}$ or 0 V, All channels, EN_2 at 3 V	no load, EN ₁ at 3 V,		10	0 16	mA
		25 Mbps				15	24	
ELECTR	RICAL CHARACTER	RISTICS	-				· ·	
I _{OFF}	Sleep mode outp	ut current	EN at 0 V, Single channel			0		μΑ
			1	ISO7240	V _{CC} - 0.4			
V_{OH}	High-level output	voltage	I _{OH} = -4 mA, See Figure 1	ISO724x (5-V side)	V _{CC} - 0.8			V
			$I_{OH} = -20 \mu A$, See Figure 1	"	V _{CC} - 0.1			
W	l avv lavval avvtavvt	alta sa	I _{OL} = 4 mA, See Figure 1				0.4	W
V_{OL}	Low-level output	voitage	I_{OL} = 20 μ A, See Figure 1				0.1	V
V _{I(HYS)}	Input voltage hys	teresis				150		mV
I _{IH}	High-level input of	current	IN from O V/ to V/				10	^
I _{IL}	Low-level input c	urrent			μΑ			
Cı	Input capacitance	e to ground	IN at V_{CC} , $V_{I} = 0.4 \sin (4E6\pi t)$			2		pF
CMTI	Common-mode t immunity	ransient	V _I = V _{CC} or 0 V, See Figure 5		25	50		kV/μs

⁽¹⁾ For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V.



INSTRUMENTS

SLLS868H-SEPTEMBER 2007-REVISED OCTOBER 2008

SWITCHING CHARACTERISTICS: V_{CC1} at 3.3-V and V_{CC2} at 5-V OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay	1007040		22		51	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	ISO724xC	See Figure 1			3	ns
t _{PLH} , t _{PHL}	Propagation delay	100724vM	See Figure 1	12		30	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	ISO724xM			1	2	ns
	Dort to part alcour (2)	ISO724xC				10	
t _{sk(pp)}	Part-to-part skew (2)	ISO724xM			0	5	ns
	Observed to the control of the (3)	ISO724xC				2.5	
t _{sk(o)}	Channel-to-channel output skew (3)	ISO724xM			0	1	ns
t _r	Output signal rise time		See Figure 1		2		
t _f	Output signal fall time				2		ns
t _{PHZ}	Propagation delay, high-level-to-high-im	pedance output			15	20	
t _{PZH}	Propagation delay, high-impedance-to-h	igh-level output			15	20	
t _{PLZ}	Propagation delay, low-level-to-high-imp	edance output	See Figure 2		15	20	ns
t _{PZL}	Propagation delay, high-impedance-to-lo	w-level output			15	20	
t _{fS}	Failsafe output delay time from input por	wer loss	See Figure 3		12		μs
t _{wake}	Wake time from input disable	See Figure 4		15		μs	
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO724xM	150 Mbps NRZ data input, Same polarity input on all channels, See Figure 6		1		ns

⁽¹⁾ Also known as pulse skew

⁽²⁾ t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

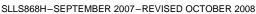
⁽³⁾ $t_{sk(o)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.



ELECTRICAL CHARACTERISTICS: V_{CC1} and V_{CC2} at 3.3 $V^{(1)}$ OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT					'	
	ICO7240C/M	Quiescent	$V_I = V_{CC}$ or 0 V, all channels, no load,		0.5	1	A
	ISO7240C/M	25 Mbps	EN ₂ at 3 V		3	5	mA
	ISO7241C/M	Quiescent	$V_I = V_{CC}$ or 0 V, all channels, no load,		4	7	
I _{CC1}		25 Mbps	EN ₁ at 3 V, EN ₂ at 3 V		6.5	11	mA
	ISO7242C/M	Quiescent	$V_I = V_{CC}$ or 0 V, all channels, no load,		6	10	ША
		25 Mbps	EN ₁ at 3 V, EN ₂ at 3 V		9	14	
	ISO7240C/M	Quiescent	$V_I = V_{CC}$ or 0 V, all channels, no load,		9.5	15	mΛ
	1307240C/W	25 Mbps	EN ₂ at 3 V		10.5	17	mA
Land	ISO7241C/M	Quiescent	$V_I = V_{CC}$ or 0 V, all channels, no load,		8	13	mA
I _{CC2}		25 Mbps	EN_1 at 3 V, EN_2 at 3 V		11.5	18	
	ISO7242C/M	Quiescent	$V_I = V_{CC}$ or 0 V, all channels, no load,		6	10	ША
		25 Mbps	EN ₁ at 3 V, EN ₂ at 3 V		9	14	
ELECTR	CICAL CHARACTERISTICS						
I _{OFF}	Sleep mode output current		EN at 0 V, single channel		0		μΑ
V_{OH}	High-level output voltage		I _{OH} = -4 mA, See Figure 1	$V_{CC} - 0.4$			V
VOH	r light-level output voltage		$I_{OH} = -20 \mu A$, See Figure 1	V _{CC} - 0.1			V
V_{OL}	Low-level output voltage		I _{OL} = 4 mA, See Figure 1			0.4	V
VOL	Low-level output voltage		I_{OL} = 20 μ A, See Figure 1			0.1	V
$V_{I(HYS)}$	Input voltage hysteresis				150		mV
I _{IH}	High-level input current		IN from 0 V or V _{CC}			10	μΑ
I_{IL}	Low-level input current		IIA HOHLO A OL ACC	-10			μА
C _I	Input capacitance to ground		IN at V_{CC} , $V_{I} = 0.4 \sin (4E6\pi t)$		2		pF
CMTI	Common-mode transient im	munity	V _I = V _{CC} or 0 V, See Figure 5	25	50		kV/μs

⁽¹⁾ For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V.







SWITCHING CHARACTERISTICS: V_{CC1} and V_{CC2} at 3.3-V OPERATION

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
t _{PLH} , t _{PHL}	Propagation delay	ISO724xC	704,0			56	50
PWD	Pulse-width distortion t _{PHL} - t _{PLH} ⁽¹⁾	150724xC	See Figure 4			4	ns
t _{PLH} , t _{PHL}	Propagation delay	ISO724xM	See Figure 1	12		34	20
PWD	Pulse-width distortion t _{PHL} - t _{PLH} ⁽¹⁾	150724XIVI			1	2	ns
	Dort to part alray (2)	ISO724xC				10	20
t _{sk(pp)}	Part-to-part skew ⁽²⁾	ISO724xM			0	5	ns
t _{sk(o)} C	Channel to about a start along (3)	ISO724xC				3.5	
	Channel-to-channel output skew (3)	ISO724xM			0	1	ns
t _r Output signal rise time			See Figure 1		2		ns
t _f	Output signal fall time	See Figure 1		2		ns	
t _{PHZ}	Propagation delay, high-level-to-high-impe	edance output			15	20	ns
t _{PZH}	Propagation delay, high-impedance-to-hig	h-level output	See Figure 2		15	20	
t _{PLZ}	Propagation delay, low-level-to-high-imped	dance output			15	20	
t _{PZL}	Propagation delay, high-impedance-to-low			15	20		
t _{fs}	Failsafe output delay time from input power	See Figure 3		18		μs	
t _{wake}	Wake time from input disable	See Figure 4		15		μs	
t _{jit(pp)}	eak-to-peak eye-pattern jitter ISO724xM		150 Mbps PRBS NRZ data input, same polarity input on all channels, See Figure 6		1		ns

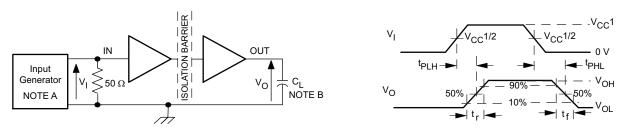
⁽¹⁾ Also referred to as pulse skew.

⁽²⁾ t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

⁽³⁾ t_{sk(o)} is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.

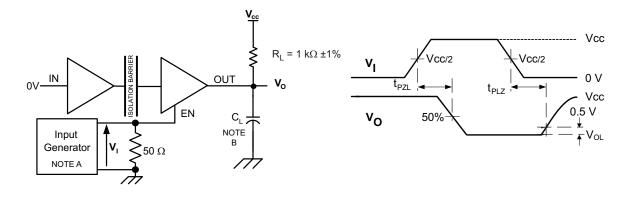


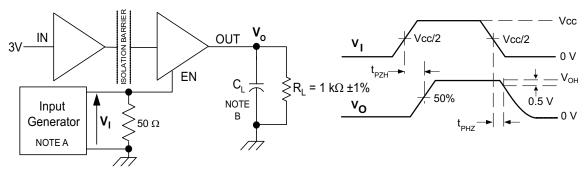
PARAMETER MEASUREMENT INFORMATION



- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, $t_r \leq$ 3 ns, $t_f \leq$ 3 ns, $Z_O = 50\Omega$.
- B. $C_L = 15$ pF and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 1. Switching Characteristic Test Circuit and Voltage Waveforms



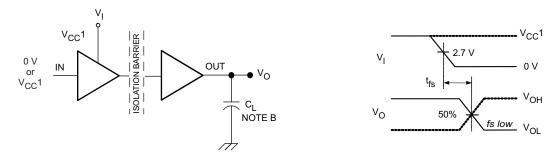


- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, $t_r \leq$ 3 ns, $t_f \leq$ 3 ns, $Z_O = 50\Omega$.
- B. $C_L = 15$ pF and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 2. Enable/Disable Propagation Delay Time Test Circuit and Waveform

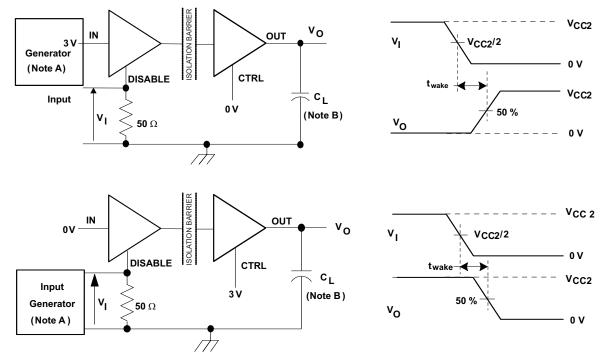


PARAMETER MEASUREMENT INFORMATION (continued)



- A. $C_L = 15$ pF and includes instrumentation and fixture capacitance within $\pm 20\%$.
- B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, $t_r \leq$ 3 ns, $t_f \leq$ 3 ns, $Z_O = 50\Omega$.

Figure 3. Failsafe Delay Time Test Circuit and Voltage Waveforms



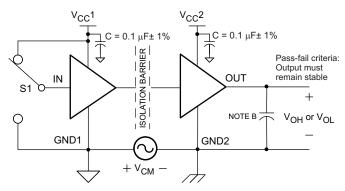
NOTE: Which ever test yields the longest time is used in this datasheet

A. Whichever test yields the longest time is used in this data sheet.

Figure 4. Wake Time From Input Disable Test Circuit and Voltage Waveforms

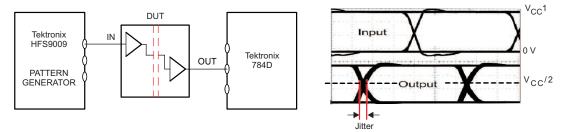


PARAMETER MEASUREMENT INFORMATION (continued)



- A. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within $\pm 20\%$.
- B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, $t_r \leq$ 3 ns, $t_f \leq$ 3 ns, $Z_O = 50\Omega$.

Figure 5. Common-Mode Transient Immunity Test Circuit and Voltage Waveform



NOTE: PRBS bit pattern run length is 2¹⁶ – 1. Transition time is 800 ps. NRZ data input has no more than five consecutive 1s or 0s

Figure 6. Peak-to-Peak Eye-Pattern Jitter Test Circuit and Voltage Waveform

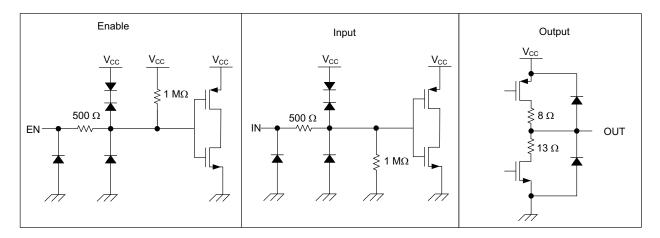


DEVICE INFORMATION

PACKAGE CHARACTERISTICS

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
L(I01)	Minimum air gap (Clearance)	Shortest terminal-to-terminal distance through air	8.34			mm
L(102)	Minimum external tracking (Creepage)	Shortest terminal-to-terminal distance across the package surface	8.1			mm
	Minimum Internal Gap (Internal Clearance)	Distance through the insulation	0.008			mm
R _{IO}	Isolation resistance	Input to output, V_{IO} = 500 V, all pins on each side of the barrier tied together creating a two-terminal device		>10 ¹²		Ω
C _{IO}	Barrier capacitance Input to output	V _I = 0.4 sin (4E6πt)		2		pF
C _I	Input capacitance to ground	V _I = 0.4 sin (4E6πt)		2		pF

DEVICE I/O SCHEMATICS



REGULATORY INFORMATION

VDE	VDE CSA			
Certified according to IEC 60747-5-2	Approved under CSA Component Acceptance Notice	Recognized under 1577 Component Recognition Program ⁽¹⁾		
File Number: 40016131	File Number: 1698195	File Number: E181974		

⁽¹⁾ Production tested ≥ 3000 Vrms for 1 second in accordance with UL 1577.

THERMAL CHARACTERISTICS

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
θ _{IA} Junction-to-air		Low-K Thermal Resistance ⁽¹⁾		168		°C/W
θ_{JA} Junction-to-air	Junction-to-all	High-K Thermal Resistance 96.1		96.1		C/VV
θ_{JB}	Junction-to-Board Thermal Resistance			61		°C/W
θ_{JC}	Junction-to-Case Thermal Resistance			48		°C/W
P_D	Device Power Dissipation	$V_{CC1} = V_{CC2} = 5.5 \text{ V}, T_J = 150^{\circ}\text{C}, C_L = 15 \text{ pF},$ Input a 50% duty cycle square wave			220	mW

⁽¹⁾ Tested in accordance with the Low-K or High-K thermal metric definitions of EIA/JESD51-3 for leaded surface mount packages.

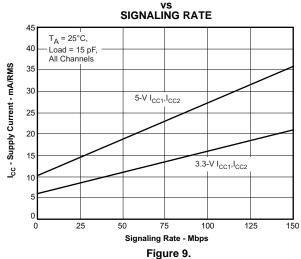


TYPICAL CHARACTERISTIC CURVES

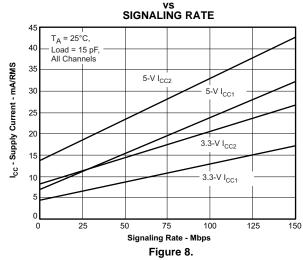
ISO7240C/M RMS SUPPLY CURRENT vs SIGNALING RATE 45 T_A = 25°C, 40 Load = 15 pF, All Channels I_{CC} - Supply Current - mA/RMS 35 5-V I_{CC2} 30 25 20 15 10 3.3-V I_{CC1} 5 0 75 100 125 <u>150</u> Signaling Rate - Mbps

ISO7242C/M RMS SUPPLY CURRENT vs

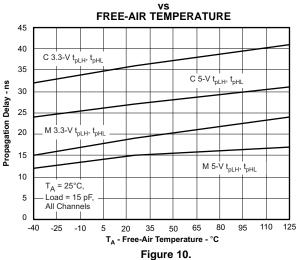
Figure 7.



ISO7241C/M RMS SUPPLY CURRENT



PROPAGATION DELAY





TYPICAL CHARACTERISTIC CURVES (continued)

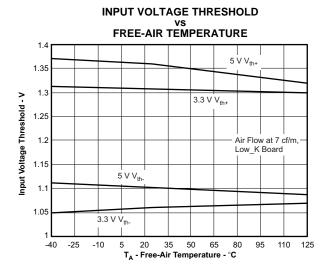
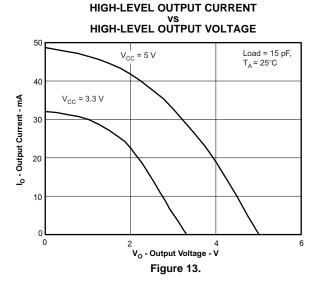
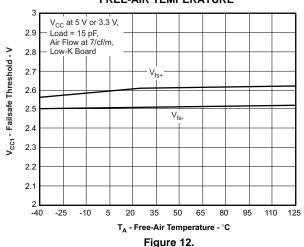


Figure 11.







. .9....

LOW-LEVEL OUTPUT CURRENT vs LOW-LEVEL OUTPUT VOLTAGE

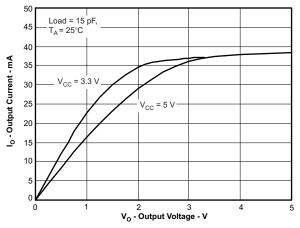


Figure 14.



APPLICATION INFORMATION

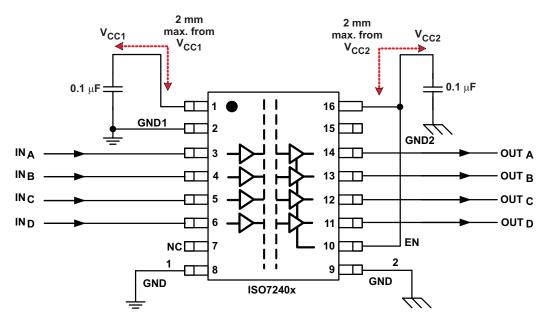


Figure 15. Typical ISO7240x Application Circuit

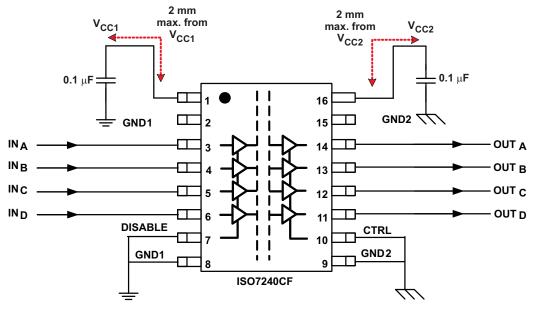


Figure 16. Typical ISO7240CF Failsafe-Low Application Circuit



LIFE EXPECTANCY vs. WORKING VOLTAGE

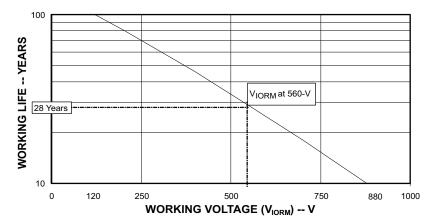


Figure 17. Time-Dependant Dielectric Breakdown Testing Results







PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
ISO7240CDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7240CDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7240CDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7240CDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7240CFDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7240CFDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7240CFDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7240CFDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7240MDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7240MDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7240MDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7240MDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7241CDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7241CDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7241CDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7241CDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7241MDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7241MDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7241MDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7241MDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7242CDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7242CDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7242CDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7242CDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7242MDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR



PACKAGE OPTION ADDENDUM

28-Oct-2008

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins F	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp (3)
ISO7242MDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7242MDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7242MDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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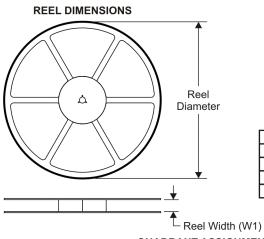
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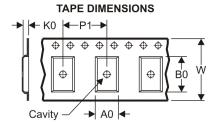




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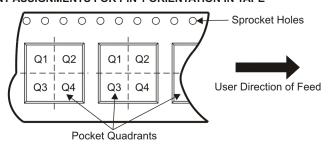
TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

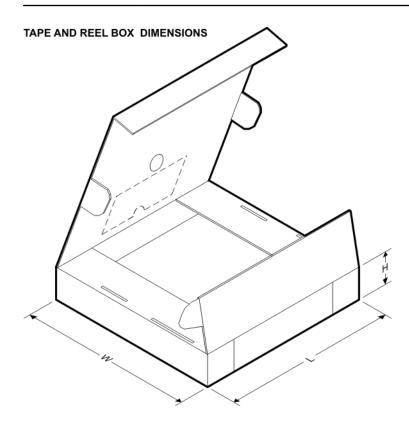
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO7240CDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7240CFDWR	SOIC	DW	16	2000	330.0	16.4	10.9	10.78	3.0	12.0	16.0	Q1
ISO7240MDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7241CDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7241MDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7242CDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7242MDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1



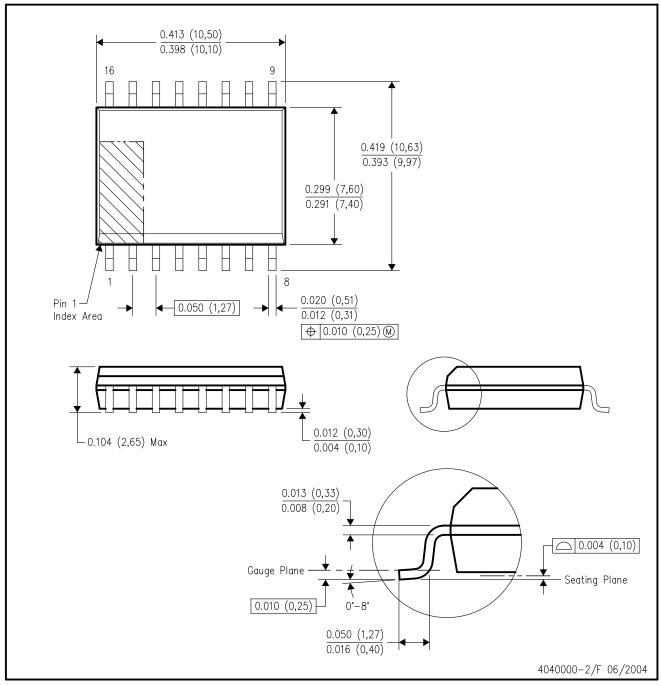


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ISO7240CDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7240CFDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7240MDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7241CDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7241MDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7242CDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7242MDWR	SOIC	DW	16	2000	358.0	335.0	35.0

DW (R-PDSO-G16)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AA.



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